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**Specification for radio disturbance and immunity measuring apparatus and methods –
Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements**

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –
Partie 2-1: Méthodes de mesure des perturbations et de l'immunité – Mesures des perturbations conduites**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

**SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY
MEASURING APPARATUS AND METHODS –****Part 2-1: Methods of measurement of disturbances and immunity –
Conducted disturbance measurements**

FOREWORD

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This Consolidated version of CISPR 16-2-1 bears the edition number 3.1. It consists of the third edition (2014-02) [documents CISPR/A/1053/FDIS and CISPR/A/1062/RVD] and its amendment 1 (2017-06) [documents CISPR/A/1168/CDV and CISPR/A/1201/RVC]. The technical content is identical to the base edition and its amendment.

This Final version does not show where the technical content is modified by amendment 1. A separate Redline version with all changes highlighted is available in this publication.

International Standard CISPR 16-2-1 has been prepared by CISPR subcommittee A: Radio-interference measurements and statistical methods.

This third edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition: Methods of measurement using a new type of ancillary equipment – the CDNE – are added.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of CISPR 16 series under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, can be found on the IEC website.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements

1 Scope

This part of CISPR 16 is designated a basic standard that specifies the methods of measurement of disturbance phenomena in general in the frequency range 9 kHz to 18 GHz and especially of conducted disturbance phenomena in the frequency range 9 kHz to 30 MHz. The CDNE extends the frequency range of conducted disturbance measurements to 300 Hz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 14-1, *Electromagnetic compatibility – Requirements for household appliances, electric tools and similar apparatus – Part 1: Emission*

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-1-2:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements*

CISPR 16-4-2, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Uncertainty in EMC measurements*

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at <http://www.electropedia.org>)

3 Terms, definitions and abbreviations

3.1 Terms and definitions